Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10815839	HAN, DAVID
Examiner	Art Unit
Nguyen, Tuan D	2614

SEARCHED				
Class	Subclass	Date	Examiner	
381	371,370,378,316,318,320,321	3/1/07	TN	
379	430	3/1/07	TN	

SEARCH NOTES					
Search Notes	Date	Examiner			
Brian Ensey	2/28/07	TN			

	INTERFERENCE SEA	RCH	
Class	Subclass	Date	Examiner

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